

System and Method for Automatic Extraction of Testing Information From a Functional Specification

ABSTRACT OF THE DISCLOSURE

A system and method for testing a development device includes extracting multiple parameters of the development device from a product specification for the development device. The parameters being arranged in a predetermined first order. The parameters are stored in a testing data file. The testing data file can be input into a test bench system being coupled to the development device. The test bench system can test the development device.